



# **Rump Session: Advanced Silicon Technology Foundry Access Options for DoD Research**

**Dr. Michael Gaitan**

**National Institute of Standards of  
Technology**

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# Integration of IC Foundries and MEMS Fabrication

**Michael Gaitan**

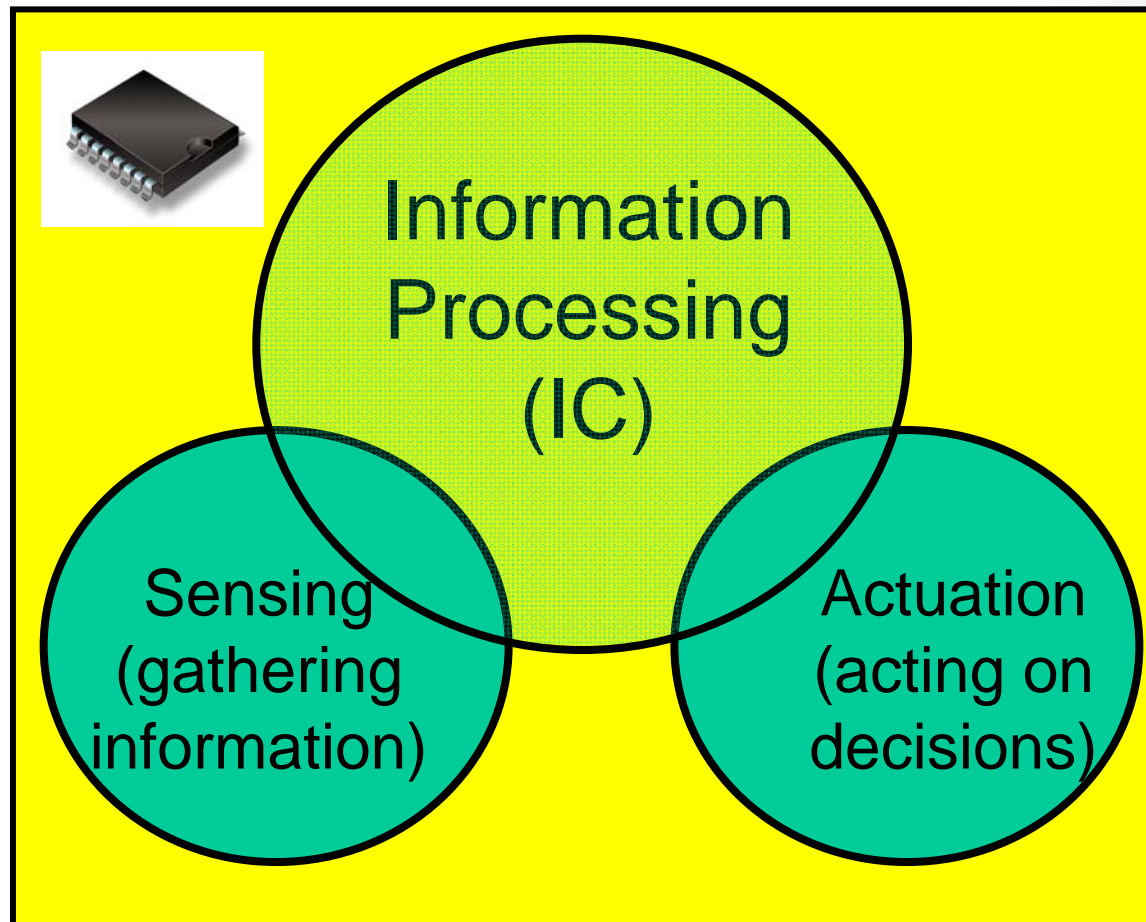
Leader, Enabling Devices Group  
National Institute of Standards and Technology  
Gaithersburg MD 20899 USA  
gaitan@nist.gov

**MTO Symposium 2009**

RUMP Session: Advanced Silicon Technology Foundry  
Access Options for DoD Research

March 3, 2008  
San Jose, California

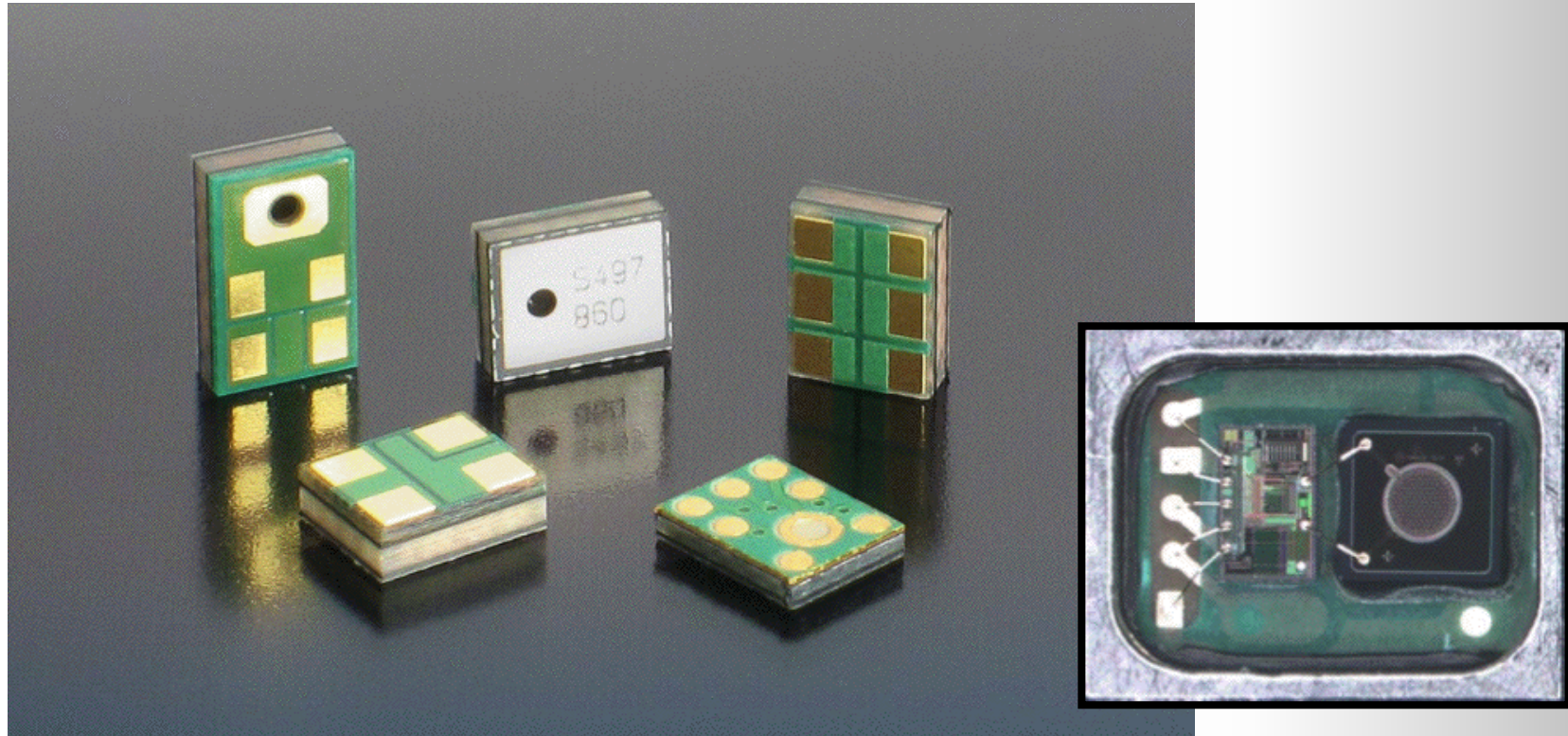
# Microsystems Technologies



# Fabrication of MEMS

- No Integration
  - Discrete Devices
- Co-Integration
  - System in a Package
- Monolithic Integration
  - System on a Chip

# Example: Co-Integration



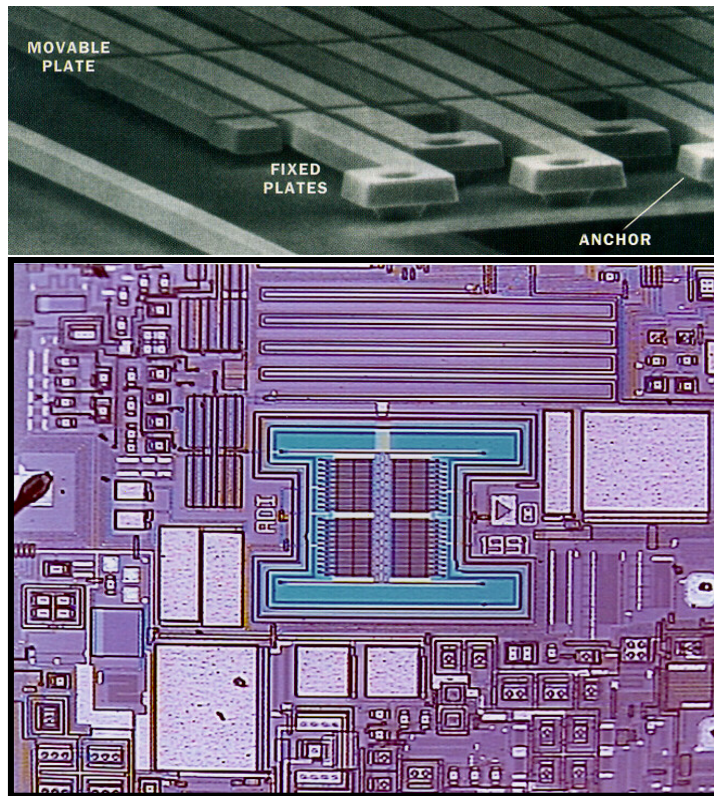
*Dan Giesecke  
Presentation to SEMI on MEMS Microphone*

Knowles Acoustics

[http://www.knowles.com/search/products/m\\_surface\\_mount.jsp](http://www.knowles.com/search/products/m_surface_mount.jsp)

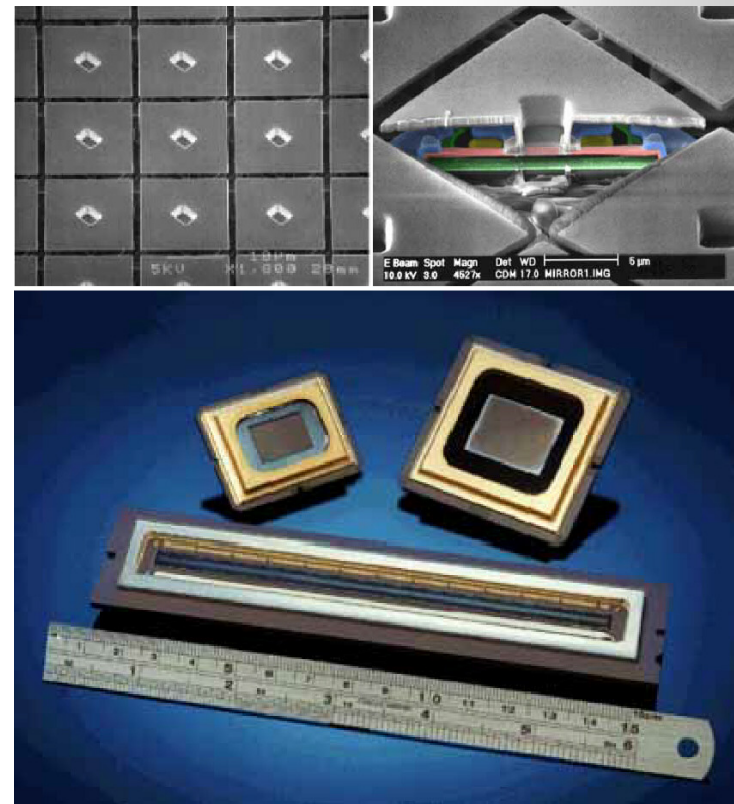


# Example: Monolithic Integration



Analog Devices  
Accelerometer

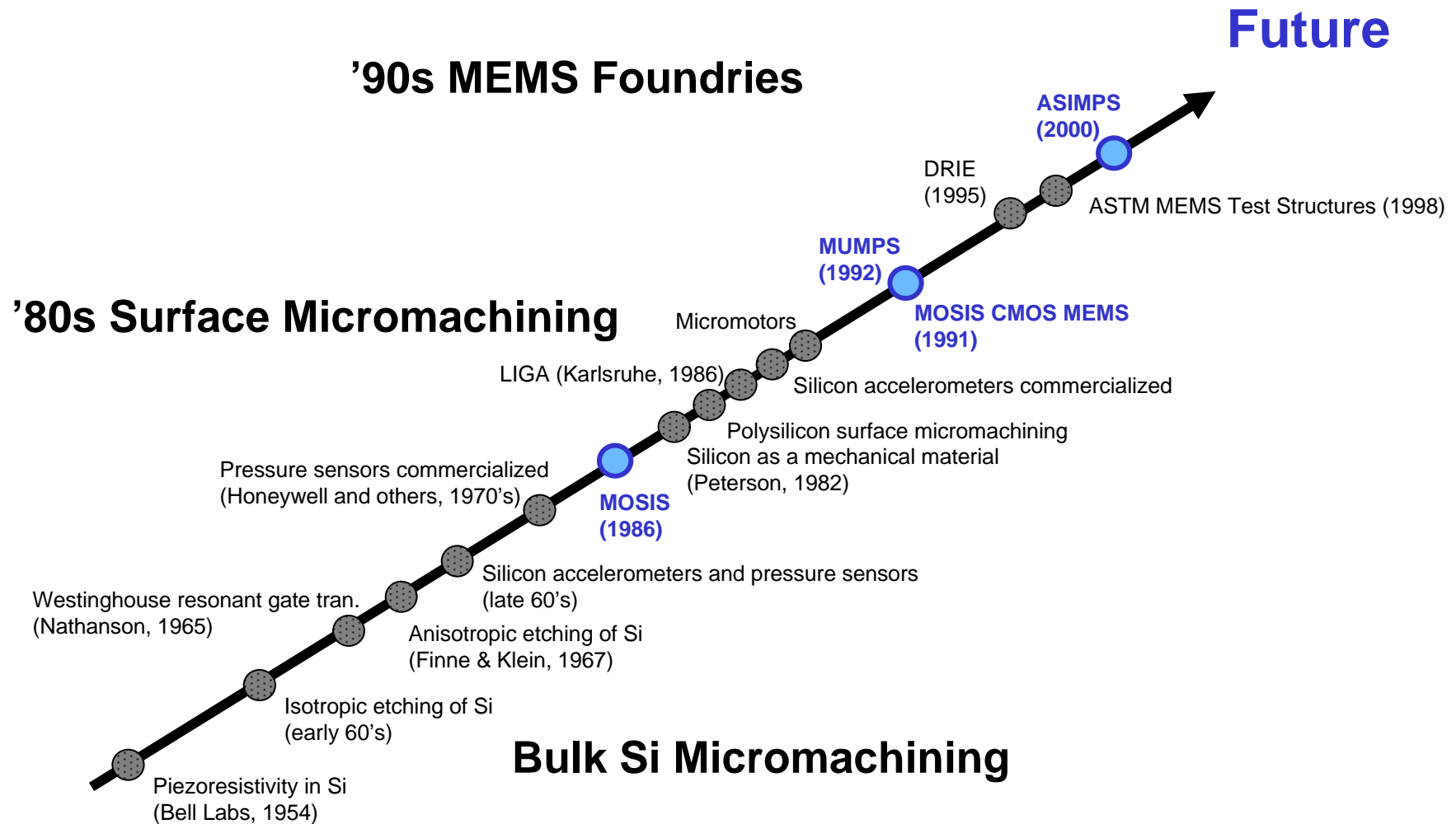
<http://www.analog.com/mems>



Texas Instruments  
Deformable Mirror Display

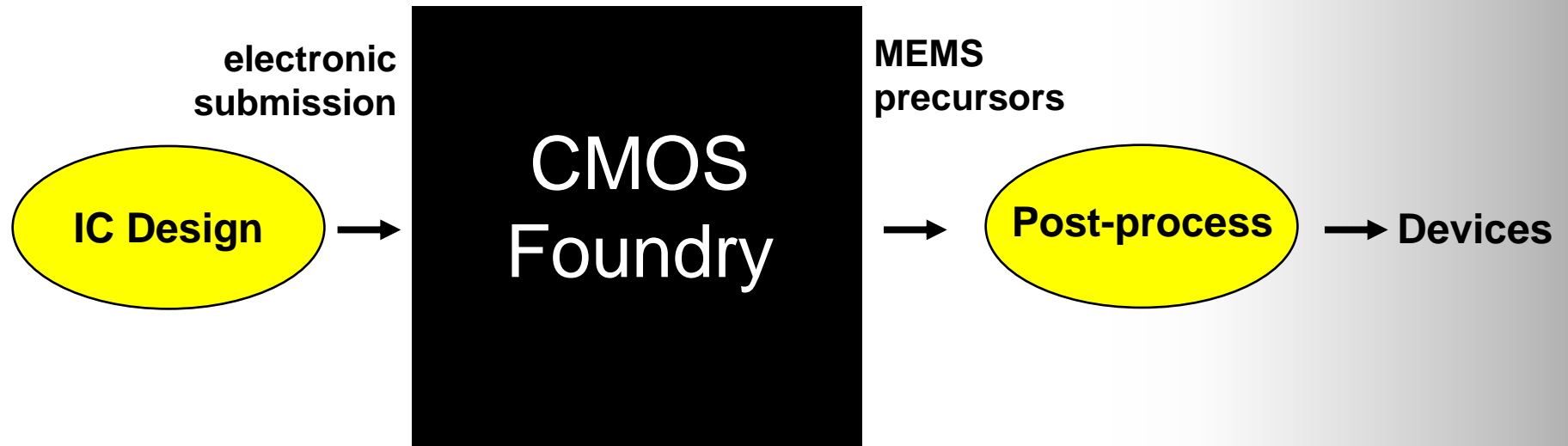
<http://www.dlp.com>

# Timeline of Foundry Services

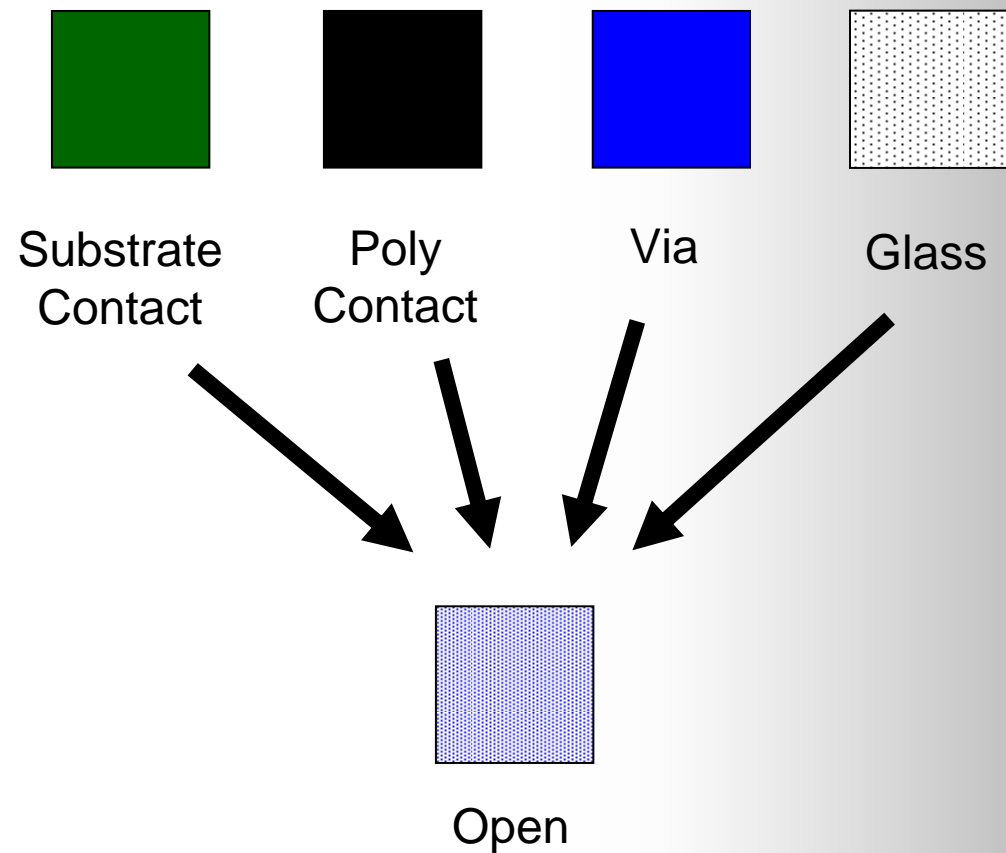
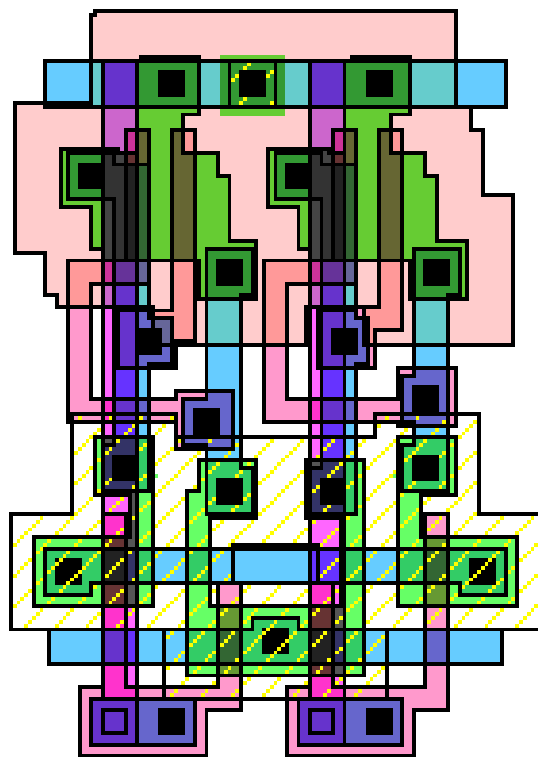




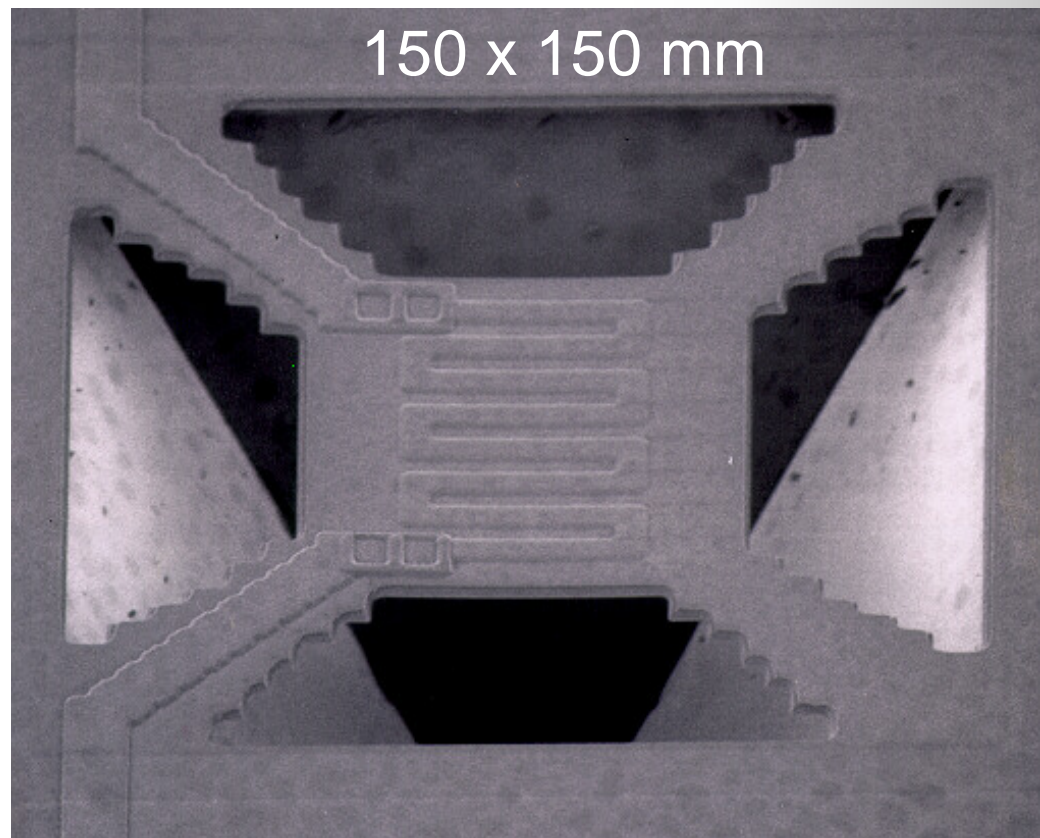
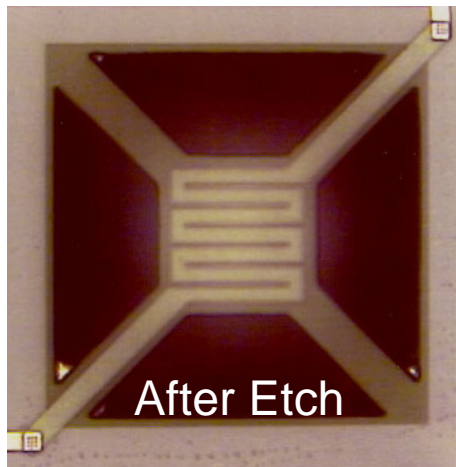
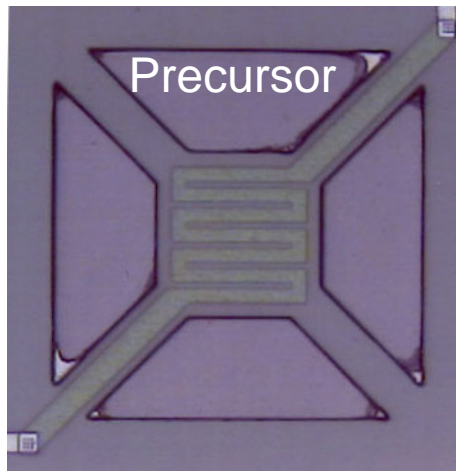
# CMOS Foundry MEMS



# Design: Open Tile (Stacked Via Opening)



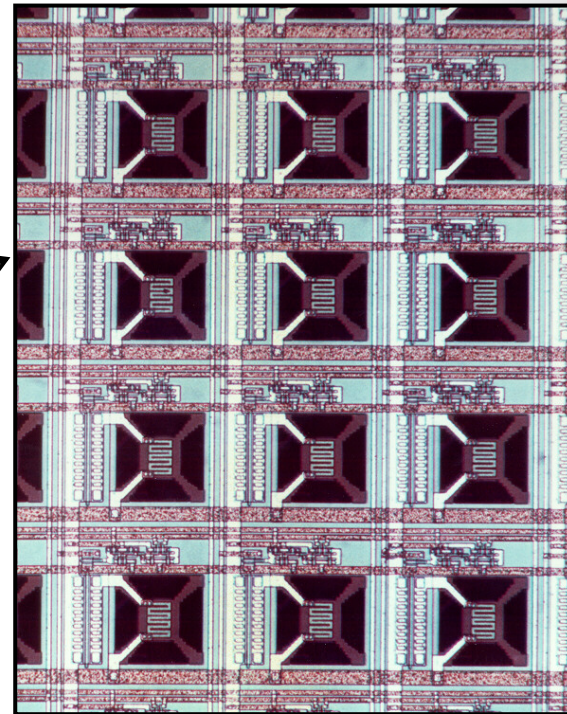
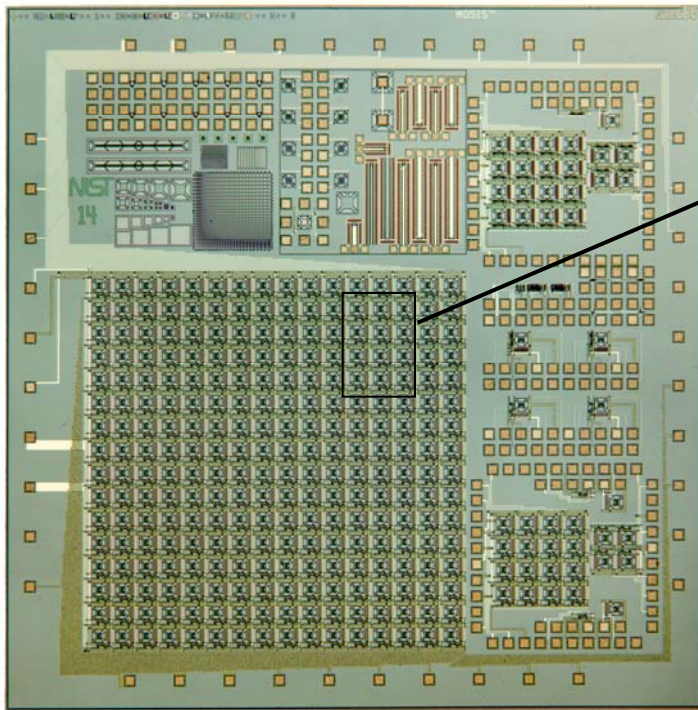
# Example: Microheating Elements



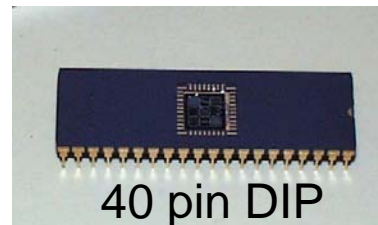
Parameswaren, Electron Device Letters, 12 (2), 57-59, Feb 1991.

# Thermal Array

16x16 Array



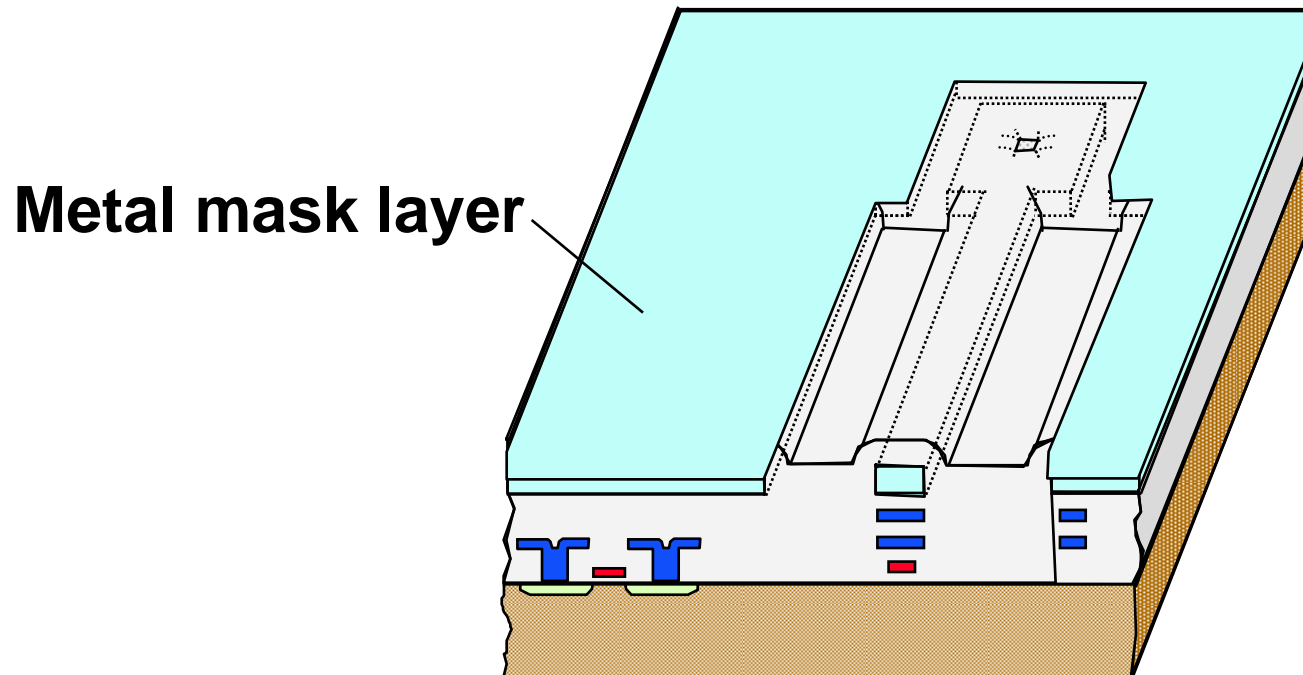
6x6 mm



40 pin DIP

# ASIMPS Post-CMOS Micromachining

## Application-Specific Integrated MEMS Process Service

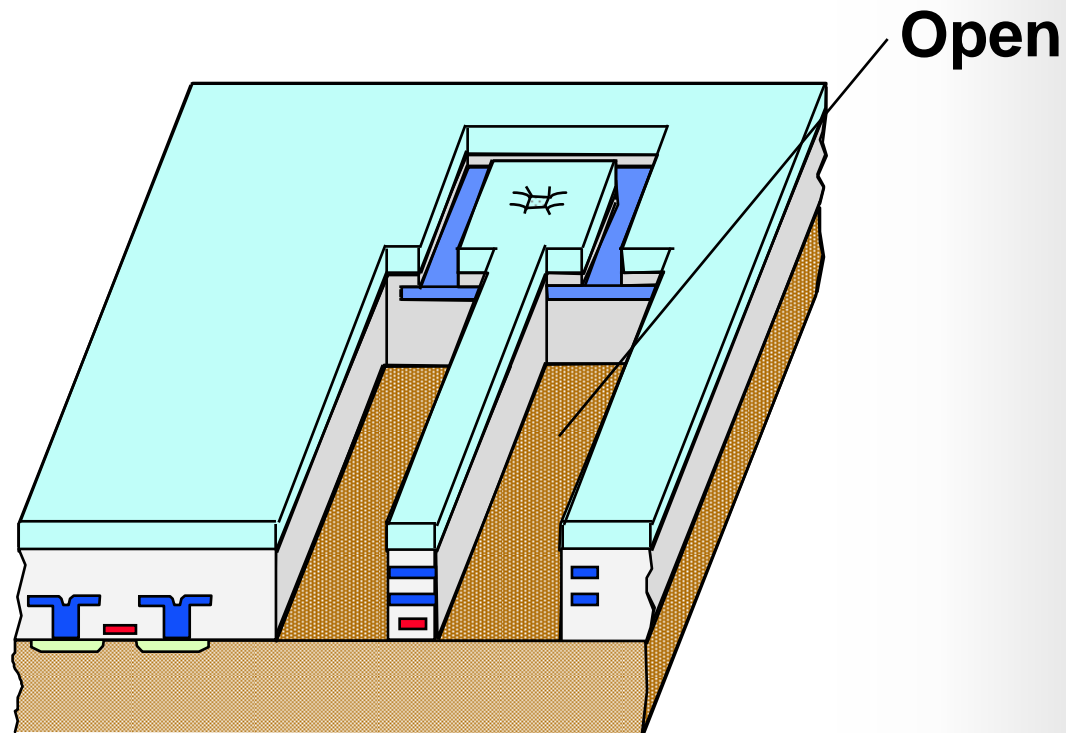


**Carnegie Mellon University (CMU)**

Fedder *et al.*, Sensors & Actuators A, v.57, no.2, 1996



# ASIMPS Post-CMOS Micromachining

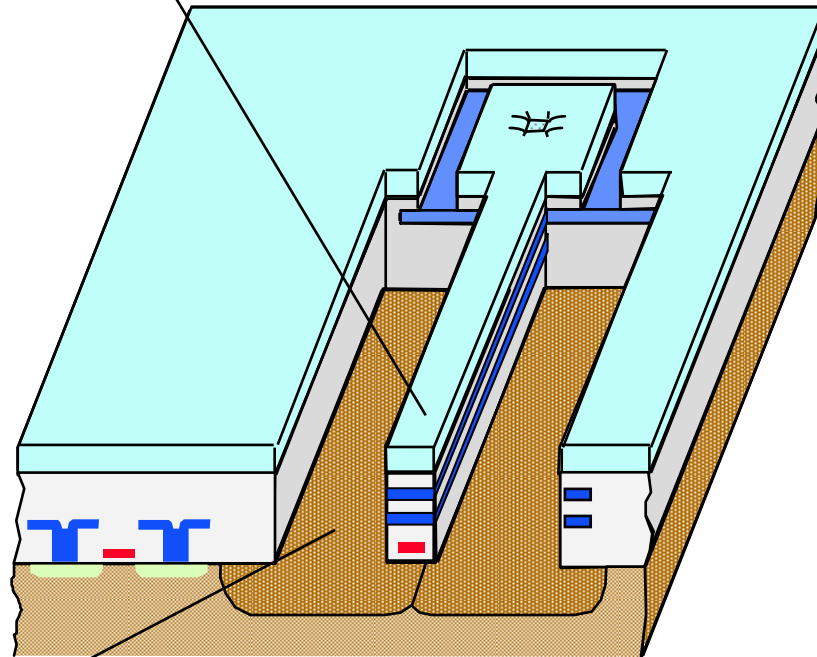


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# ASIMPS Post-CMOS Micromachining

Composite beam

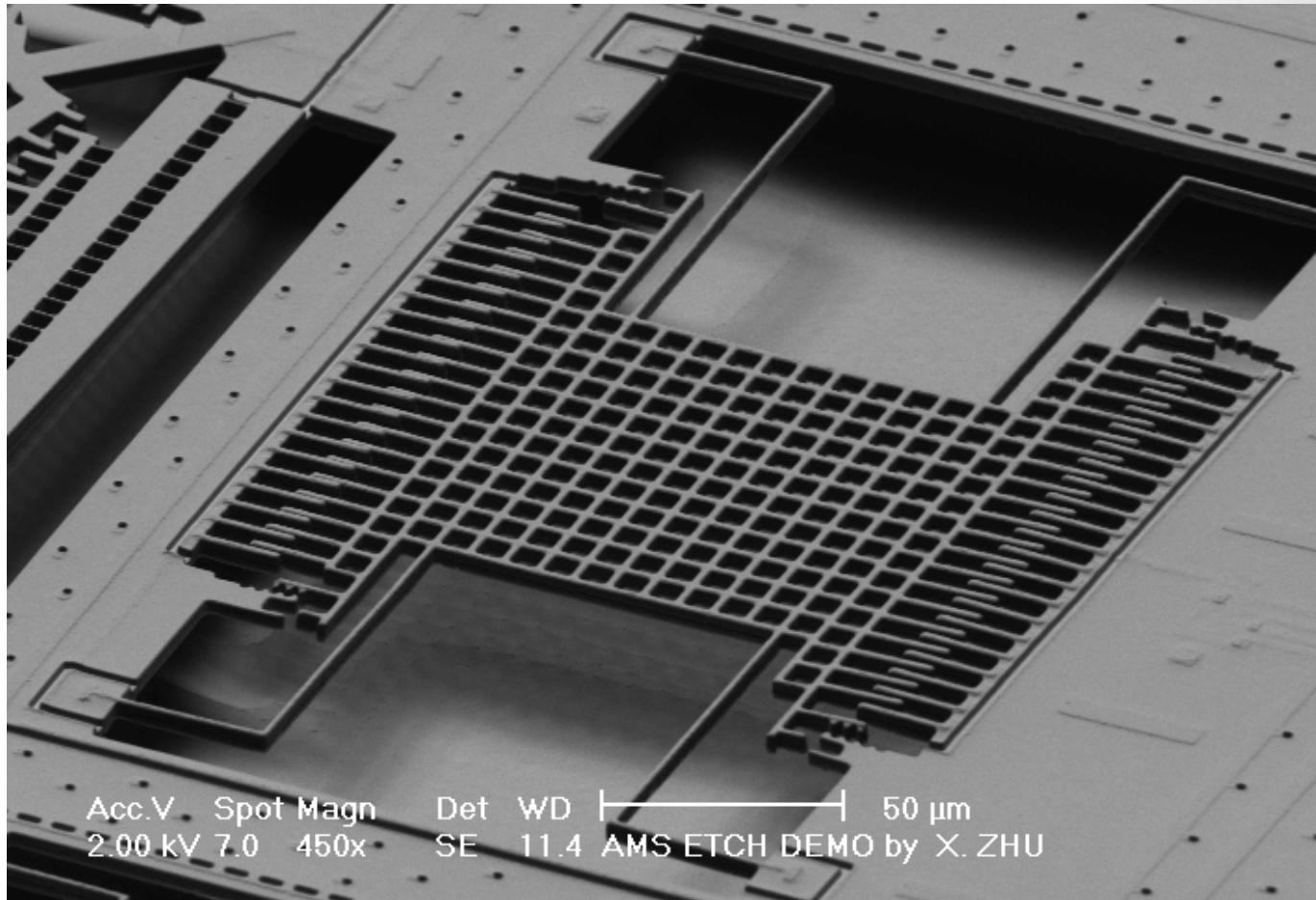


Anisotropically  
Etched

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Fedder *et al.*, Sensors & Actuators A, v.57, no.2, 1996

# ASIMPS Post-CMOS Micromachining



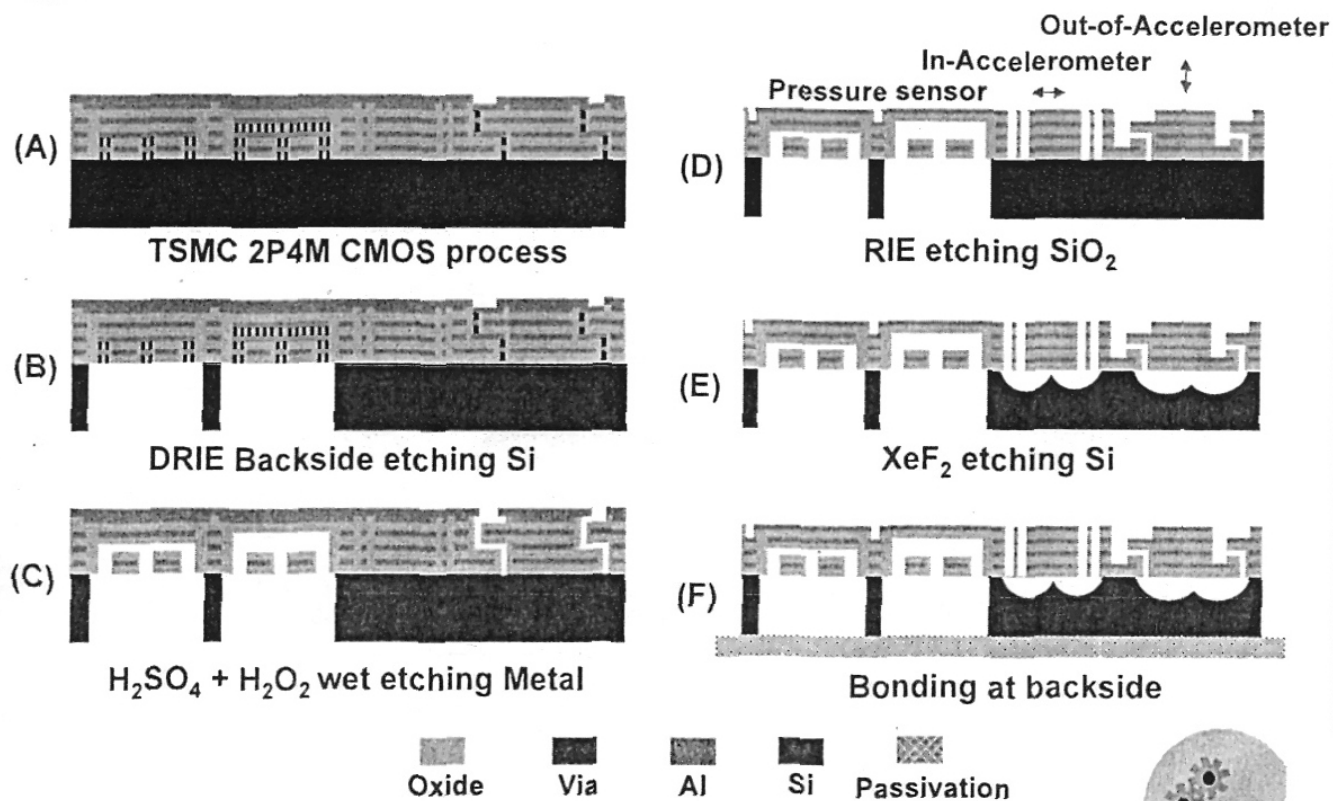
**ASIMPS: AMS 0.6 mm, 3-metal**

<http://www.ece.cmu.edu/~mems/projects/asimps>

# TSMC CMOS MEMS



## Double-side CMOS post processing



Sun, Wang, Tsai, and Fang, *IEEE MEMS'08, Tucson, AZ. 2008*



# CMEMS™

CMOS wafers + MEMS on top

SiGe deposited on top of CMOS



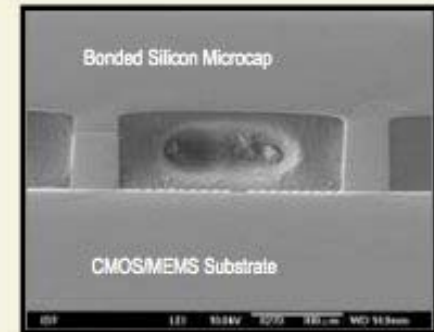
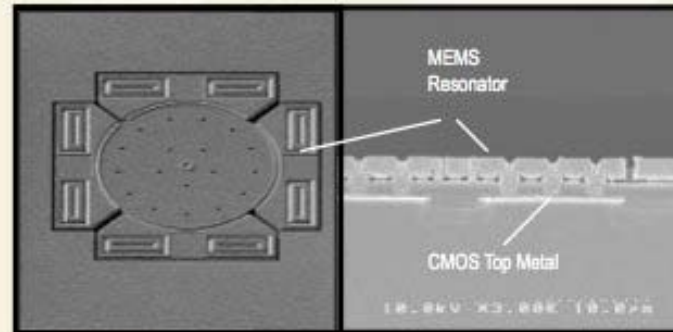
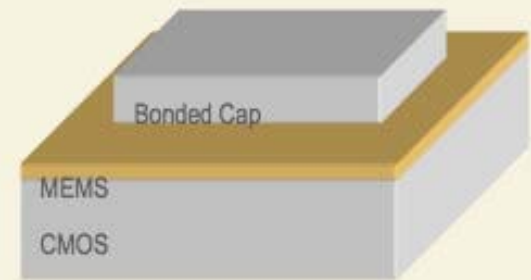
**Fabricate  
CMOS Wafer**



**Back End of Line  
Integrated MEMS**



**MEMS Release and Eutectic  
Bonding Encapsulation**



- › Wafers utilize existing, standard processes
- › MEMS process independent of wafer technology

- › Low temperature SiGe film deposition
- › Modular, back-end compatible process
- › Enables banks of multiple MEMS
- › Integrate multiple MEMS functions (sensor, filter, etc.)

- › Mainstream MEMS technique
- › Compatible with standard plastic packaging
- › Small form factor



SILICON CLOCKS

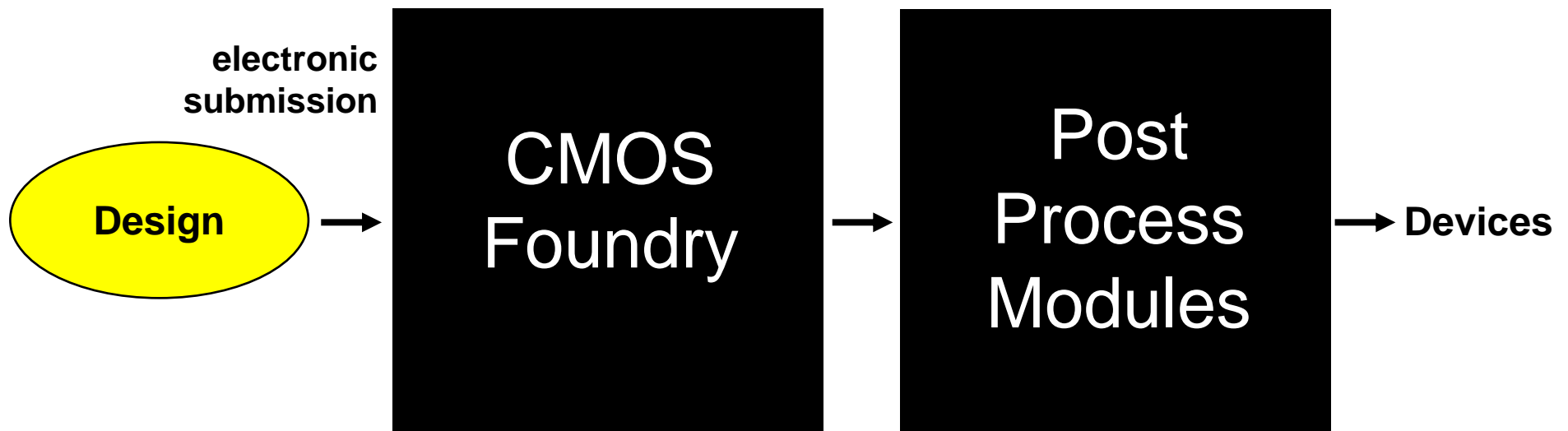
Emmanuel Quevy, Silicon Clocks

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# Moving Forward

## Fully Supported Post Process Modules



Needed

- Affordability
- A variety of process flows
- Long term commitment
- CAD toolsets and design libraries
- Packaging

# Summary

- CMOS MEMS post processes enable
  - Accessibility to monolithic integration
  - Device arrays with circuits
  - Circuits can be used to increase performance
- Issues
  - Co-Integrate or Integrate?
  - Can we live with (de facto) standard fabrication process modules?